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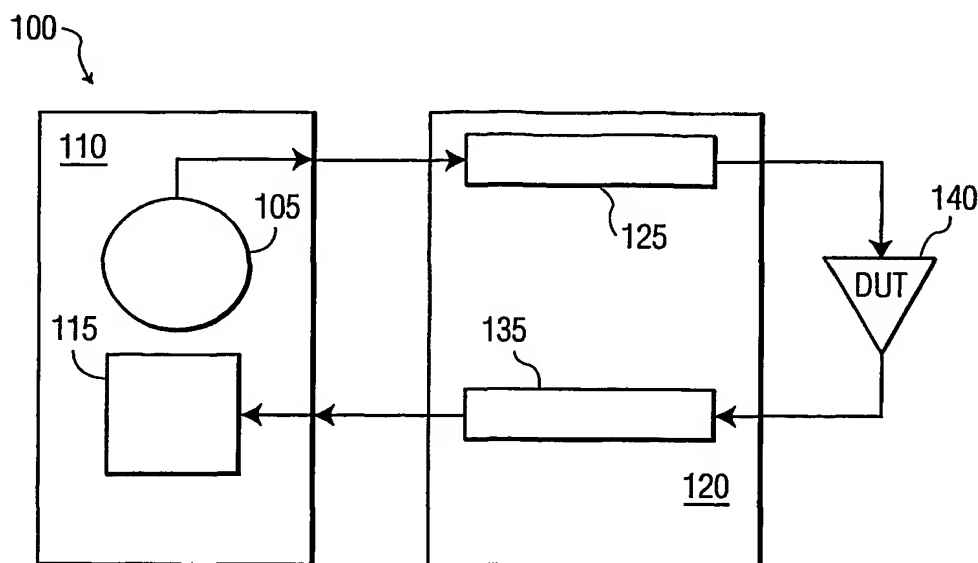
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(54) Title: CALIBRATION OF TESTER AND TESTBOARD BY GOLDEN SAMPLE



(57) Abstract: In performing testing on Automatic Test Equipment (ATE) it is a challenge to accurately generate and measure RF (radio frequency) power. In an example embodiment, in a test apparatus (100) used for measuring the input and output characteristics of an amplifier (140), there is a method for determining test program parameters. The method (200) comprises calculating input loss from the test apparatus power source to the input of the amplifier (220), defining an input loss correction factor. The output loss from the amplifier output (220) to the power meter of the test apparatus is calculated, defining an output loss correction factor. Using the input loss correction factor (230), a real input power level is determined and using the output loss correction factor (230), a real output level is determined.

**Declarations under Rule 4.17:**

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- as to the applicant's entitlement to claim the priority of the earlier application (Rule 4.17(iii)) for all designations

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